


Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/589,003	ITOH ET AL.	
	Examiner	Art Unit	
	Jae Lee	2823	

SEARCHED			
Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST search: see attached search histories	6/4/2007	JML
IEEE search: CuCl and ionic crystal search for semiconductors	6/5/2007	JML